

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10632082	LEE ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	Han, Jason M	2875

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
362	217-225, 260, 646	6/4/2008	JMH
349	58, 70-71	6/4/2008	JMH
439	56, 235	6/4/2008	JMH

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
Search Update - EAST (US-PGPUB, USPAT, USOCR, EPO, JPO, DERWENT) - See Printout	9/26/2006	JMH
Search Update - EAST (US-PGPUB, USPAT, USOCR, EPO, JPO, DERWENT) - See Printout	11/8/2007	JMH
Search Update - EAST (US-PGPUB, USPAT, USOCR, EPO, JPO, DERWENT) - See Printout	6/4/2008	JMH

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>